

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/078,742 SLATTER ET AL.	
		Examiner	Art Unit	Page 1 of 1 Lin Ye 2615

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,667,771	12-2003	Kweon, Sup Heuk	348/373
	B	US-2003/0156217	08-2003	Ejima, Satoshi	348/373
	C	US-5,594,498	01-1997	Fraley, Walter C.	348/158
	D	US-6,292,213	09-2001	Jones, Michael J.	348/61
	E	US-5,610,678	03-1997	Tsuboi et al.	396/373
	F	US-6,396,403	05-2002	Haner, Lenora A.	340/573.4
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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